



Coating Loss Measurements on Thin Fused Silica Substrates

LIGO-G020119-00-Z

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Outline

- Goals of Coating Loss Experiment
- Plan for Coating Measurements on Thin Substrates
- Thin Substrate Experimental Set-up & Sources of Loss
- Modifications for Future Coatings Work

Review of Coating Program

- Levin (1998) showed coatings could be a limiting source of loss.
- Preliminary measurements at Glasgow and Syracuse indicated $\phi_{\text{coating}} \approx 2.5 \times 10^{-4} \Rightarrow \text{Test Mass } Q\text{'s} \approx 10^7$
- Advanced LIGO requires $\phi_{\text{coating}} \approx 10^{-5}$ for Sapphire masses and 200 Mpc range.
- Coating program initiated:
 - » Thin Substrates with birefringent readout (Syracuse & MIT)
 - » Thick Substrates with interferometric readout (Glasgow & Stanford)

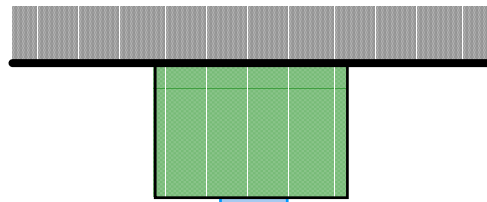
Thin Substrate Measurements

- Uncoated, Super-polished Disks
(Mindrum & Wave Precision), $Q = 6\text{--}20$ million
- Annealed, Uncoated, Superpolished Disks, $Q \approx 45$ million
- Coated Disk, 2-layers, ($\lambda/4 \text{ Ta}_2\text{O}_5$, $\lambda/4 \text{ SiO}_2$) $Q \approx 9$ million
- Coated Disk, 30-layers, ($\lambda/4 \text{ Ta}_2\text{O}_5$, $\lambda/4 \text{ SiO}_2$) $Q \approx 500,000$
- Coated Disk, 30-layers, ($3\lambda/8 \text{ Ta}_2\text{O}_5$, $\lambda/8 \text{ SiO}_2$) $Q \approx 400,000$
- Coated Disk, 60-layers, ($\lambda/8 \text{ Ta}_2\text{O}_5$, $\lambda/8 \text{ SiO}_2$) $Q \approx 500,000$



Support

Collet

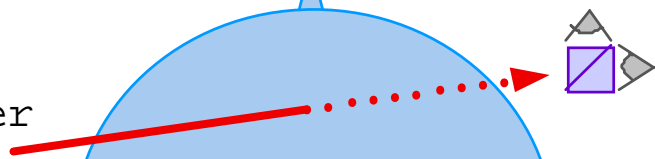


Isolation Bob



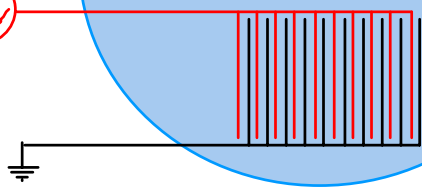
Birefringen Sensor

Laser

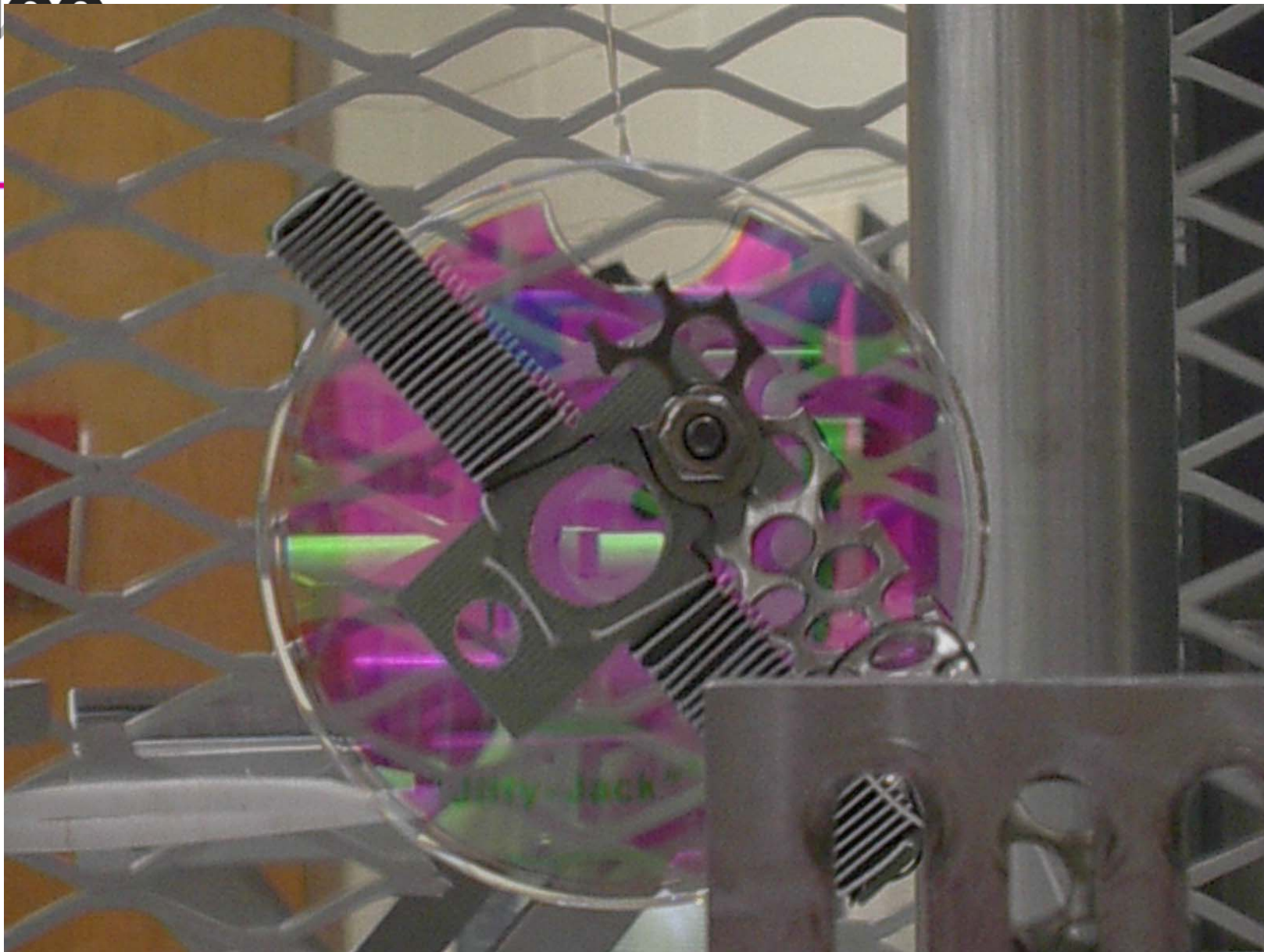


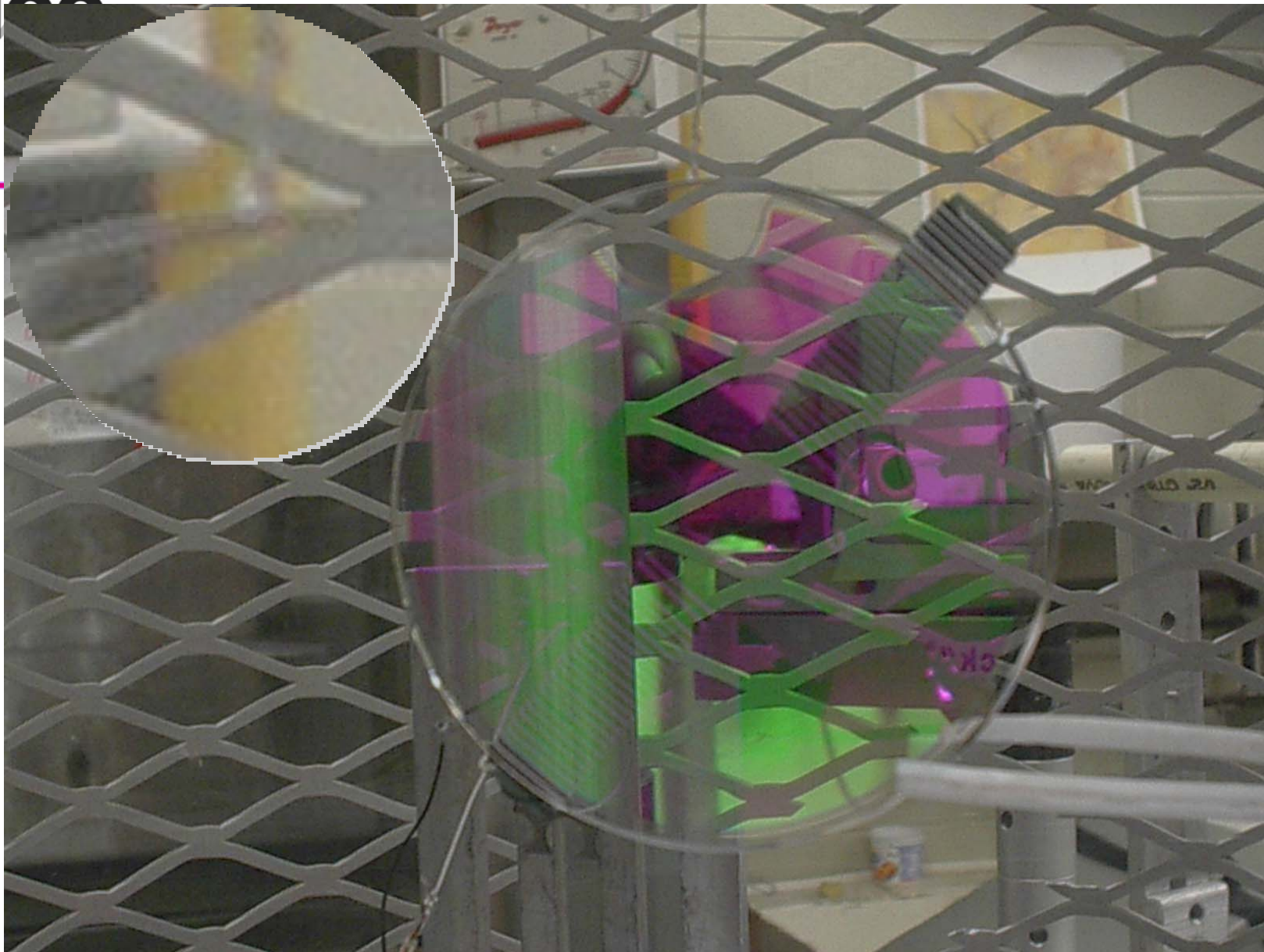
Gradient E
Field Excitor

500 V AC +
500 V DC





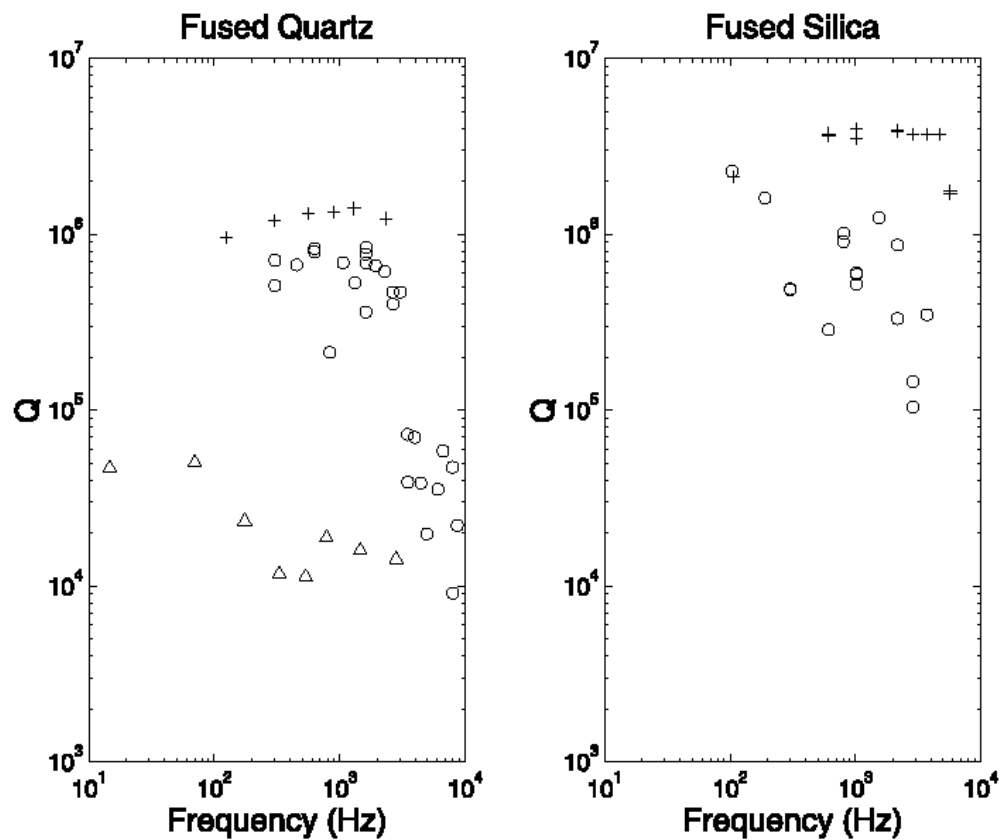




Benefits of the Thin Disk Method

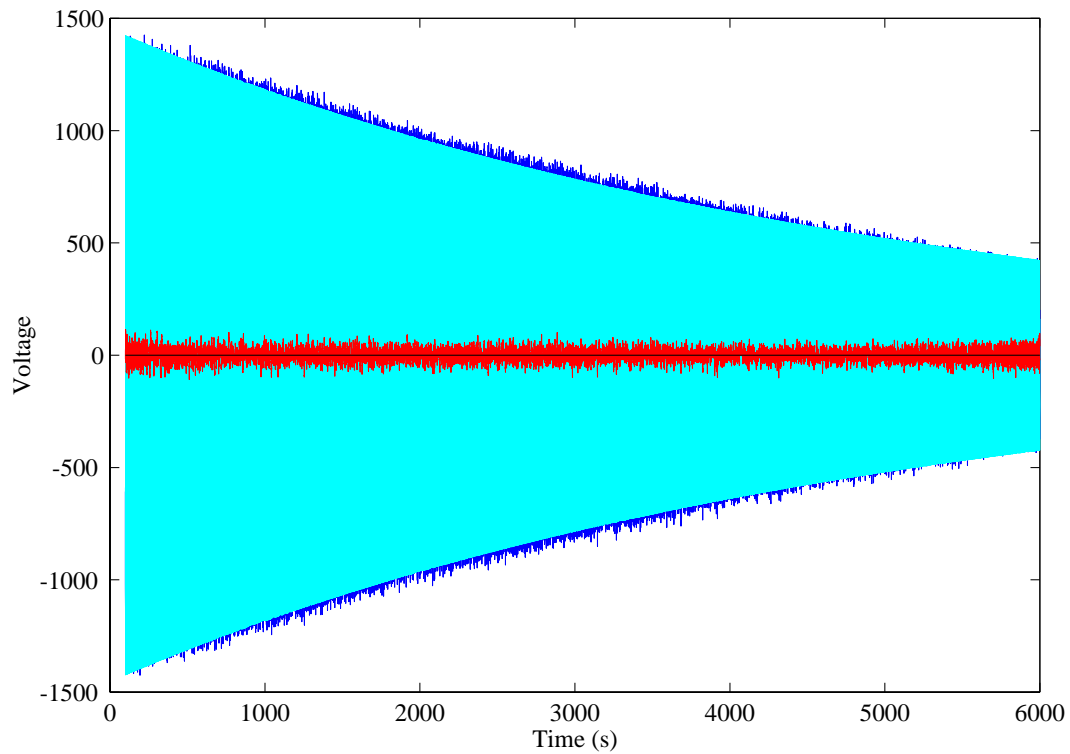
- Geometry enhances ΔQ due to coatings (factor 40)
- Suspension methods (welding, collet & bob) are low loss
- Tiny ($\approx 100 \mu\text{m}$) welds do not disturb coatings ($\Delta T \approx 0$)
- In-air feedback allows for mode identification
- Birefringence Readout has high SNR & clean analysis
- Excellent Agreement of Results between labs

Effect of the Isolation Bob



Annealed, Uncoated Disk

File: 120401a.dat, Freq = 2781.100Hz, Tau = 4863.282s, Q = $4.249\text{e}+07 \pm 2.339\text{e}+04$









Thin Disk Method for Sapphire?

- Benefits of low cost, fast turn-around, and low noise measurements.
- Problems with attachment
 - » Bonding not preferable due to loss
 - » Is welding sapphire possible? Even if possible, amorphous weld would likely have higher loss.
 - » Develop a TAMA-like suspension using pins holding the sample edges

